Bus buffer/line driver; 3-state

Rev. 09 — 22 June 2009

Product data sheet

1. General description

74AHC1G125 and 74AHCT1G125 are high-speed Si-gate CMOS devices. They provide one non-inverting buffer/line driver with 3-state output. The 3-state output is controlled by the output enable input (\overline{OE}). A HIGH at \overline{OE} causes the output to assume a high-impedance OFF-state.

The AHC device has CMOS input switching levels and supply voltage range 2 V to 5.5 V.

The AHCT device has TTL input switching levels and supply voltage range 4.5 V to 5.5 V.

2. Features

- Symmetrical output impedance
- High noise immunity
- Low power dissipation
- Balanced propagation delays
- Multiple package options
- ESD protection:
 - HBM JESD22-A114E: exceeds 2000 V
 - MM JESD22-A115-A: exceeds 200 V
 - CDM JESD22-C101C: exceeds 1000 V
- Specified from –40 °C to +125 °C

3. Ordering information

Table 1.Ordering information

Type number	Package									
	Temperature range	Name	Description	Version						
74AHC1G125GW	–40 °C to +125 °C	TSSOP5	plastic thin shrink small outline package; 5 leads; body width 1.25 mm	SOT353-1						
74AHCT1G125GW										
74AHC1G125GV	–40 °C to +125 °C	SC-74A	plastic surface-mounted package; 5 leads	SOT753						
74AHCT1G125GV										
74AHC1G125GM	–40 °C to +125 °C	XSON6	plastic extremely thin small outline package; no	SOT886						
74AHCT1G125GM			leads; 6 terminals; body $1 \times 1.45 \times 0.5$ mm							
74AHC1G125GF	–40 °C to +125 °C	XSON6	plastic extremely thin small outline package;	SOT891						
74AHCT1G125GF			no leads; 6 terminals; body $1 \times 1 \times 0.5$ mm							



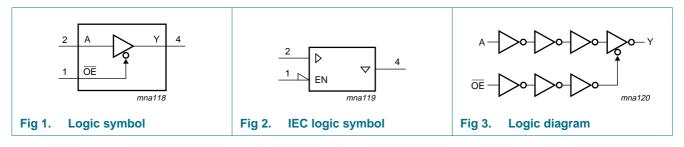
Bus buffer/line driver; 3-state

4. Marking

Table 2. Marking codes	
Type number	Marking ^[1]
74AHC1G125GW	AM
74AHCT1G125GW	СМ
74AHC1G125GV	A25
74AHCT1G125GV	C25
74AHC1G125GM	AM
74AHCT1G125GM	СМ
74AHC1G125GF	AM
74AHCT1G125GF	СМ

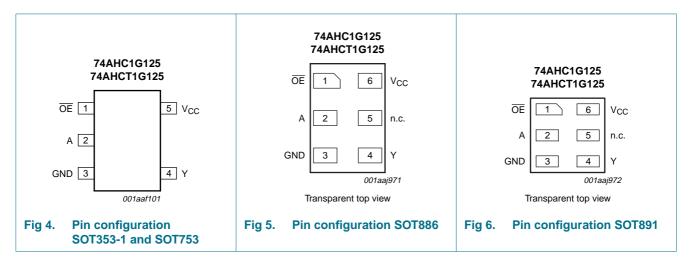
[1] The pin 1 indicator is located on the lower left corner of the device, below the marking code.

5. Functional diagram



6. Pinning information

6.1 Pinning



74AHC_AHCT1G125_9

Bus buffer/line driver; 3-state

6.2 Pin description

Table 3. Pi	n description		
Symbol	Pin		Description
	SOT353-1/SOT753	SOT886/SOT891	
OE	1	1	output enable input
A	2	2	data input
GND	3	3	ground (0 V)
Y	4	4	data output
n.c.	-	5	not connected
V _{CC}	5	6	supply voltage

7. Functional description

Table 4.Function table

H = HIGH voltage level; L = LOW voltage level; X = don't care; Z = high-impedance OFF-state

Inputs OE		Output
ŌE	Α	Y
L	L	L
L	Н	Н
н	Х	Z

8. Limiting values

Table 5.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{CC}	supply voltage		-0.5	+7.0	V
VI	input voltage		-0.5	+7.0	V
I _{IK}	input clamping current	V _I < -0.5 V	<u>[1]</u> –20	-	mA
I _{OK}	output clamping current	$V_{\rm O}$ < –0.5 V or V_{\rm O} > V _{CC} + 0.5 V	<u>[1]</u> _	±20	mA
lo	output current	$-0.5 \text{ V} < \text{V}_{\text{O}} < \text{V}_{\text{CC}} + 0.5 \text{ V}$	-	±25	mA
I _{CC}	supply current		-	75	mA
I _{GND}	ground current		-75	-	mA
T _{stg}	storage temperature		-65	+150	°C
P _{tot}	total power dissipation	$T_{amb} = -40 \ ^{\circ}C \text{ to } +125 \ ^{\circ}C$	[2] _	250	mW
,					

[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

[2] For TSSOP5 and SC-74A packages: above 87.5 °C the value of P_{tot} derates linearly with 4.0 mW/K. For XSON6 packages: above 118 °C the value of P_{tot} derates linearly with 7.8 mW/K.

Bus buffer/line driver; 3-state

9. Recommended operating conditions

Table 6. Recommended operating conditions

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	74	AHC1G1	25	74	Unit			
			Min	Тур	Max	Min	Тур	Max	
V _{CC}	supply voltage		2.0	5.0	5.5	4.5	5.0	5.5	V
VI	input voltage		0	-	5.5	0	-	5.5	V
Vo	output voltage		0	-	V_{CC}	0	-	V_{CC}	V
T _{amb}	ambient temperature		-40	+25	+125	-40	+25	+125	°C
$\Delta t / \Delta V$	input transition rise	V_{CC} = 3.3 V \pm 0.3 V	-	-	100	-	-	-	ns/V
	and fall rate	$V_{CC}=5.0~V\pm0.5~V$	-	-	20	-	-	20	ns/V

10. Static characteristics

Table 7. Static characteristics

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		25 °C		-40 °C 1	to +85 °C	_40 °C t	o +125 °C	Unit
			Min	Тур	Max	Min	Max	Min	Max	1
74AHC1	G125	'								
V _{IH}	HIGH-level	V _{CC} = 2.0 V	1.5	-	-	1.5	-	1.5	-	V
	input voltage	V _{CC} = 3.0 V	2.1	-	-	2.1	-	2.1	-	V
		$V_{CC} = 5.5 V$	3.85	-	-	3.85	-	3.85	-	V
V _{IL}	LOW-level	$V_{CC} = 2.0 V$	-	-	0.5	-	0.5	-	0.5	V
	input voltage	V _{CC} = 3.0 V	-	-	0.9	-	0.9	-	0.9	V
		$V_{CC} = 5.5 V$	-	-	1.65	-	1.65	-	1.65	V
V _{OH}	HIGH-level	$V_{I} = V_{IH} \text{ or } V_{IL}$								
	output voltage	$I_0 = -50 \ \mu\text{A}; \ V_{CC} = 2.0 \ \text{V}$	1.9	2.0	-	1.9	-	1.9	-	V
		$I_{O} = -50 \ \mu\text{A}; \ V_{CC} = 3.0 \ \text{V}$	2.9	3.0	-	2.9	-	2.9	-	V
		$I_0 = -50 \ \mu\text{A}; \ V_{CC} = 4.5 \ \text{V}$	4.4	4.5	-	4.4	-	4.4	-	V
		$I_{O} = -4.0 \text{ mA}; V_{CC} = 3.0 \text{ V}$	2.58	-	-	2.48	-	2.40	-	V
		$I_0 = -8.0 \text{ mA}; V_{CC} = 4.5 \text{ V}$	3.94	-	-	3.8	-	3.70	-	V
V _{OL}	LOW-level	$V_{I} = V_{IH} \text{ or } V_{IL}$								
	output voltage	$I_0 = 50 \ \mu A; \ V_{CC} = 2.0 \ V$	-	0	0.1	-	0.1	-	0.1	V
		$I_0 = 50 \ \mu A; \ V_{CC} = 3.0 \ V$	-	0	0.1	-	0.1	-	0.1	V
		$I_{O} = 50 \ \mu\text{A}; \ V_{CC} = 4.5 \ V$	-	0	0.1	-	0.1	-	0.1	V
		$I_0 = 4.0 \text{ mA}; V_{CC} = 3.0 \text{ V}$	-	-	0.36	-	0.44	-	0.55	V
		I_0 = 8.0 mA; V_{CC} = 4.5 V	-	-	0.36	-	0.44	-	0.55	V
I _{OZ}	OFF-state output current	$V_I = V_{CC} \text{ or GND};$ $V_{CC} = 5.5 \text{ V}$	-	-	0.25	-	2.5	-	10	μΑ
lı	input leakage current	V _I = 5.5 V or GND; V _{CC} = 0 V to 5.5 V	-	-	0.1	-	1.0	-	2.0	μΑ
I _{CC}	supply current		-	-	1.0	-	10	-	40	μΑ

Bus buffer/line driver; 3-state

		to GND (ground = 0 V).		05 00		40.00	1 OF 00	40.00 (405 00	Unit
Symbol	Parameter	Conditions		25 °C	1	-40 °C	to +85 °C	–40 °C t	o +125 °C	Unit
			Min	Тур	Max	Min	Max	Min	Max	
CI	input capacitance		-	1.5	10	-	10	-	10	pF
74AHCT	1G125									
VIH	HIGH-level input voltage	V_{CC} = 4.5 V to 5.5 V	2.0	-	-	2.0	-	2.0	-	V
VIL	LOW-level input voltage	V_{CC} = 4.5 V to 5.5 V	-	-	0.8	-	0.8	-	0.8	V
V _{OH}	HIGH-level	$V_{I} = V_{IH} \text{ or } V_{IL}; V_{CC} = 4.5 \text{ V}$								
	output voltage	I _O = -50 μA	4.4	4.5	-	4.4	-	4.4	-	V
		I _O = -8.0 mA	3.94	-	-	3.8	-	3.70	-	V
V _{OL}	V _{OL} LOW-level	$V_{I} = V_{IH} \text{ or } V_{IL}; V_{CC} = 4.5 \text{ V}$								
	output voltage	I _O = 50 μA	-	0	0.1	-	0.1	-	0.1	V
		l _O = 8.0 mA	-	-	0.36	-	0.44	-	0.55	V
I _{OZ}	OFF-state output current	$V_1 = V_{CC} \text{ or GND};$ $V_{CC} = 5.5 \text{ V}$	-	-	0.25	-	2.5	-	10	μΑ
lı	input leakage current	$V_1 = 5.5 V \text{ or GND};$ $V_{CC} = 0 V \text{ to } 5.5 V$	-	-	0.1	-	1.0	-	2.0	μΑ
I _{CC}	supply current		-	-	1.0	-	10	-	40	μΑ
Δl _{CC}	additional supply current	per input pin; $V_I = 3.4 V$; other inputs at V_{CC} or GND; $I_O = 0 A$; $V_{CC} = 5.5 V$	-	-	1.35	-	1.5	-	1.5	mA
CI	input capacitance		-	1.5	10	-	10	-	10	pF

Table 7. Static characteristics ...continued Voltages are referenced to GND (ground = 0.V)

11. Dynamic characteristics

Table 8.Dynamic characteristics

GND = 0 V; For test circuit see Figure 9.

Symbol	Parameter	Conditions		25 °C		_40 °C t	to +85 °C	–40 °C to +125 °C		Unit	
				Min	Тур	Max	Min	Max	Min	Max	
74AHC1	G125										
t _{pd}		A to Y; see Figure 7	<u>[1]</u>								
delay	V_{CC} = 3.0 V to 3.6 V	[2]									
		C _L = 15 pF		-	4.7	8.0	1.0	9.5	1.0	11.5	ns
		C _L = 50 pF		-	6.6	11.5	1.0	13.0	1.0	14.5	ns
		V_{CC} = 4.5 V to 5.5 V	[3]								
		C _L = 15 pF		-	3.4	5.5	1.0	6.5	1.0	7.0	ns
		C _L = 50 pF		-	4.8	7.5	1.0	8.5	1.0	9.5	ns

Bus buffer/line driver; 3-state

Symbol	Parameter	Conditions			25 °C		−40 °C 1	to +85 °C	–40 °C to +125 °C		Unit
				Min	Тур	Max	Min	Max	Min	Max	
en	enable time	OE to Y; see Figure 8	<u>[1]</u>								
		V_{CC} = 3.0 V to 3.6 V	[2]								
		C _L = 15 pF		-	5.0	8.0	1.0	9.5	1.0	11.5	ns
		C _L = 50 pF		-	6.9	11.5	1.0	13.0	1.0	14.5	ns
		V_{CC} = 4.5 V to 5.5 V	[3]								
		C _L = 15 pF		-	3.6	5.1	1.0	6.0	1.0	6.5	ns
		C _L = 50 pF		-	4.9	7.5	1.0	8.5	1.0	9.5	ns
dis	disable time	OE to Y; see Figure 8	<u>[1]</u>								
		V_{CC} = 3.0 V to 3.6 V	[2]								
		C _L = 15 pF		-	6.0	9.7	1.0	11.5	1.0	12.5	ns
		C _L = 50 pF		-	8.3	13.2	1.0	15.0	1.0	16.5	ns
		V_{CC} = 4.5 V to 5.5 V	[3]								
		C _L = 15 pF		-	4.1	6.8	1.0	8.0	1.0	8.5	ns
		C _L = 50 pF		-	5.7	8.8	1.0	10.0	1.0	11.0	ns
C _{PD}	power dissipation capacitance	per buffer; $C_L = 50 \text{ pF}; \text{ f} = 1 \text{ MHz};$ $V_I = \text{GND to } V_{CC}$	<u>[4]</u>	-	9	-	-	-	-	-	pF
74AHCT	1G125										
pd	propagation	A to Y; see Figure 7	<u>[1]</u>								
	delay	V_{CC} = 4.5 V to 5.5 V	[3]								
		C _L = 15 pF		-	3.4	5.5	1.0	6.5	1.0	7.0	ns
		C _L = 50 pF		-	4.8	7.5	1.0	8.5	1.0	9.5	ns
en	enable time	OE to Y; see Figure 8	[1]								
		V_{CC} = 4.5 V to 5.5 V	[3]								
		C _L = 15 pF		-	3.9	5.1	1.0	6.0	1.0	6.5	ns
		C _L = 50 pF		-	5.1	7.5	1.0	8.5	1.0	9.5	ns
dis	disable time	OE to Y; see Figure 8	[1]								
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	[3]								
		C _L = 15 pF		-	4.5	6.8	1.0	8.0	1.0	8.5	ns
		$C_{L} = 50 pF$		-	6.1	8.8	1.0	10.0	1.0	11.0	ns

Table 8.Dynamic characteristics ... continuedGND = 0 V; For test circuit see Figure 9.

Bus buffer/line driver; 3-state

Symbol	bol Parameter Conditions			25 °C		−40 °C to +85 °C		−40 °C to +125 °C		Uni	
				Min	Тур	Max	Min	Max	Min	Max	
C _{PD}		per buffer; $C_L = 50 \text{ pF}; f = 1 \text{ MHz};$ $V_I = \text{GND to } V_{CC}$	<u>[4]</u>	-	11	-	-	-	-	-	pF

Table 8. Dynamic characteristics ... continued

 t_{en} is the same as t_{PZL} and t_{PZH} . t_{dis} is the same as t_{PLZ} and t_{PHZ} .

[2] Typical values are measured at V_{CC} = 3.3 V.

- [3] Typical values are measured at V_{CC} = 5.0 V.
- [4] C_{PD} is used to determine the dynamic power dissipation P_D (μW).

 $P_{D} = C_{PD} \times V_{CC}^{2} \times f_{i} + \sum (C_{L} \times V_{CC}^{2} \times f_{o}) \text{ where:}$

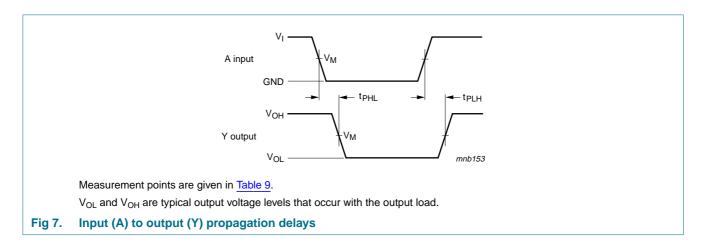
 f_i = input frequency in MHz;

 f_o = output frequency in MHz;

 C_L = output load capacitance in pF;

V_{CC} = supply voltage in Volts.

12. Waveforms



Bus buffer/line driver; 3-state

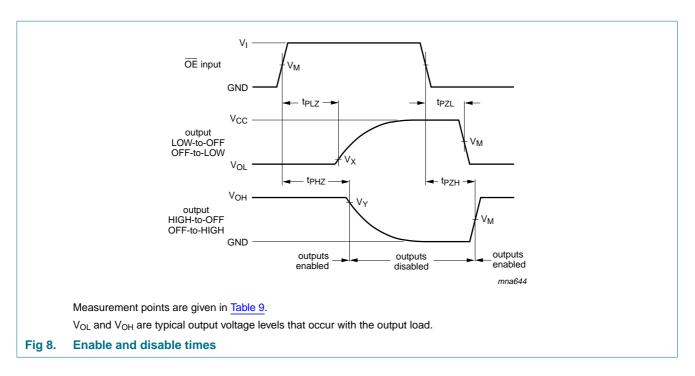


Table 9.Measurement point

Туре	Inputs		Output				
	VI	V _M	V _M	V _X	V _Y		
74AHC1G125	GND to V _{CC}	0.5V _{CC}	0.5V _{CC}	V _{OL} + 0.3 V	V _{OH} – 0.3 V		
74AHCT1G125	GND to 3.0 V	1.5 V	0.5V _{CC}	V _{OL} + 0.3 V	V _{OH} – 0.3 V		

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74AHC1G125; 74AHCT1G125

Bus buffer/line driver; 3-state

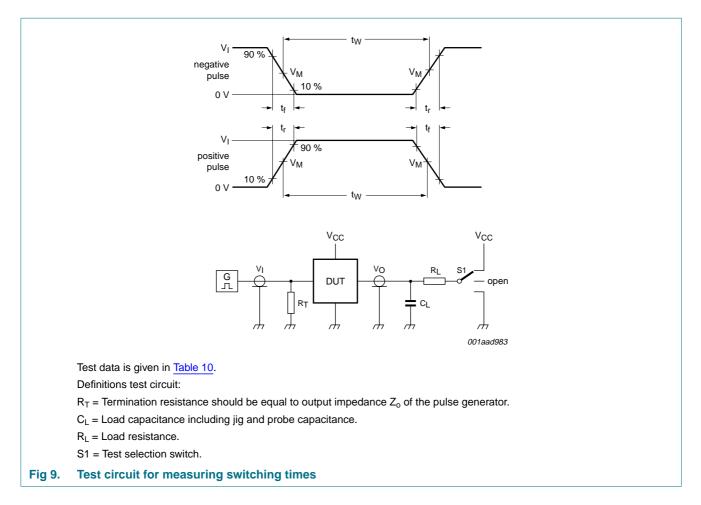


Table 10. Test data

Туре	Input		Load		S1 position		
	VI	t _r , t _f	CL	RL	t _{PHL} , t _{PLH}	t _{PZH} , t _{PHZ}	t _{PZL} , t _{PLZ}
74AHC1G125	V _{CC}	≤ 3 ns	15 pF, 50 pF	1 kΩ	open	GND	V _{CC}
74AHCT1G125	3 V	≤ 3 ns	15 pF, 50 pF	1 kΩ	open	GND	V _{CC}

Bus buffer/line driver; 3-state

13. Package outline

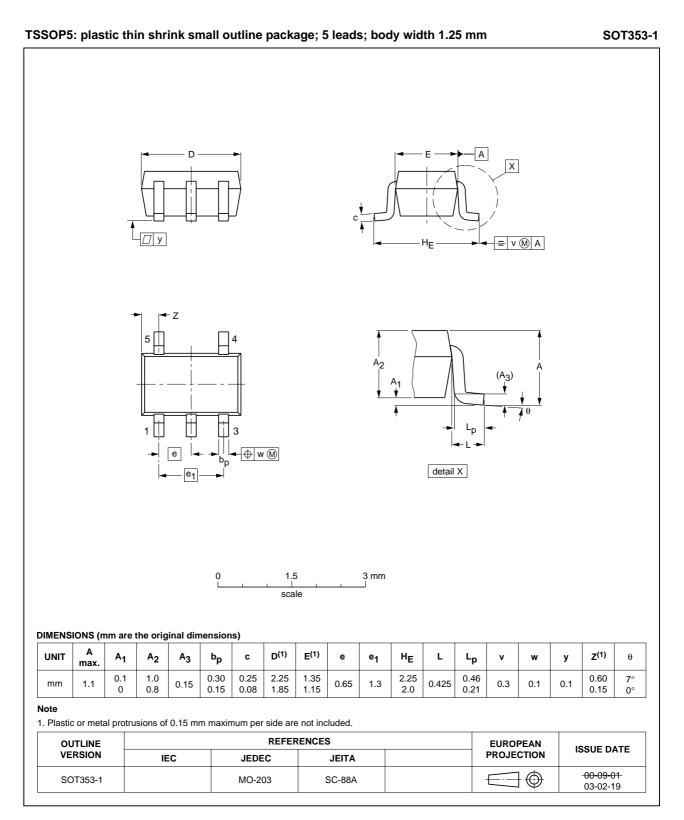


Fig 10. Package outline SOT353-1 (TSSOP5)

Bus buffer/line driver; 3-state

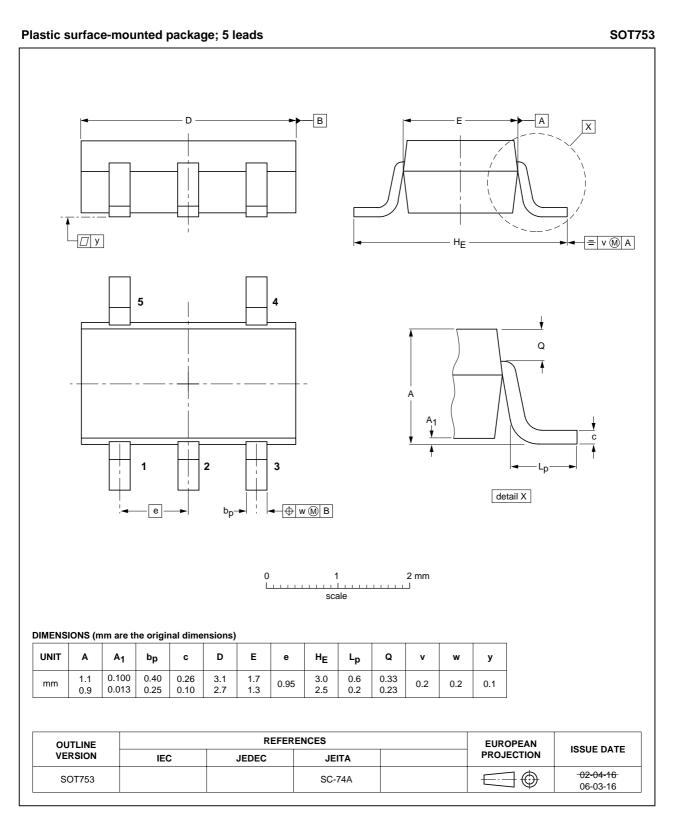


Fig 11. Package outline SOT753 (SC-74A)

Bus buffer/line driver; 3-state

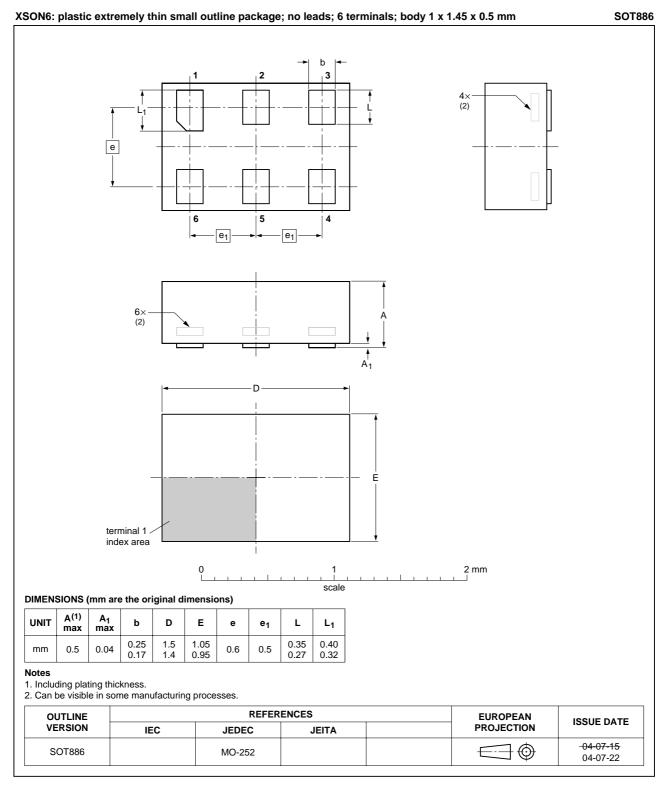


Fig 12. Package outline SOT886 (XSON6)

74AHC_AHCT1G125_9

Bus buffer/line driver; 3-state

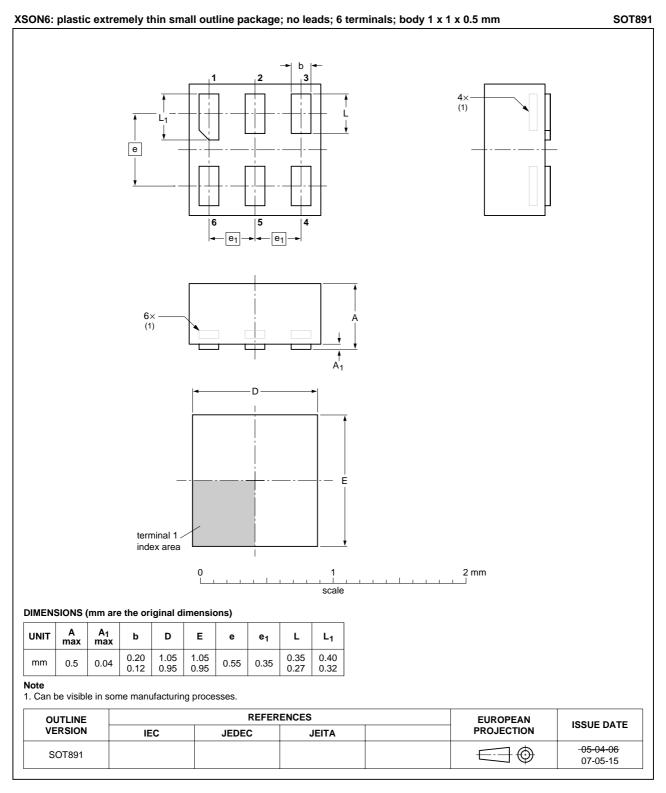


Fig 13. Package outline SOT891 (XSON6)

74AHC_AHCT1G125_9

Bus buffer/line driver; 3-state

14. Abbreviations

AcronymDescriptionCMOSComplementary Metal Oxide SemiconductorCDMCharged Device ModelDUTDevice Under TestESDElectroStatic DischargeUDMUwman Dadiu Medal	. Abbreviations			
CDMCharged Device ModelDUTDevice Under TestESDElectroStatic Discharge				
DUTDevice Under TestESDElectroStatic Discharge				
ESD ElectroStatic Discharge				
LIDM Liveren Dedu Medel				
HBM Human Body Model				
MM Machine Model				
TTL Transistor-Transistor Logic				

15. Revision history

Table 12.Revision history				
Document ID	Release date	Data sheet status	Change notice	Supersedes
74AHC_AHCT1G125_9	20090622	Product data sheet	-	74AHC_AHCT1G125_8
Modifications:	 Updated feat 	ures with multiple package opt	tion in <mark>Sectio</mark>	on <u>2</u> .
74AHC_AHCT1G125_8	20090409	Product data sheet	-	74AHC_AHCT1G125_7
Modifications:	 Package SO 	T886 and SOT891 added in Se	ection 3, Sec	tion 4 and Section 13.
74AHC_AHCT1G125_7	20070707	Product data sheet	-	74AHC_AHCT1G125_6
74AHC_AHCT1G125_6	20020606	Product specification	-	74AHC_AHCT1G125_5
74AHC_AHCT1G125_5	20020322	Product specification	-	74AHC_AHCT1G125_4
74AHC_AHCT1G125_4	20010222	Product specification	-	74AHC_AHCT1G125_3
74AHC_AHCT1G125_3	19990615	Product specification	-	74AHC_AHCT1G125_N_2
74AHC_AHCT1G125_N_2	19981207	Preliminary specification	-	74AHC_AHCT1G125_N_1
74AHC_AHCT1G125_N_1	19981125	Preliminary specification	-	-

16. Legal information

16.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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Bus buffer/line driver; 3-state

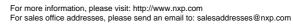
18. Contents

1	General description 1
2	Features 1
3	Ordering information 1
4	Marking 2
5	Functional diagram 2
6	Pinning information 2
6.1	Pinning 2
6.2	Pin description 3
7	Functional description 3
8	Limiting values 3
9	Recommended operating conditions 4
10	Static characteristics 4
11	Dynamic characteristics 5
12	Waveforms 7
13	Package outline 10
14	Abbreviations 14
15	Revision history 14
16	Legal information 15
16.1	Data sheet status 15
16.2	Definitions
16.3	Disclaimers
16.4	Trademarks 15
17	Contact information 15
18	Contents 16

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